

























Exams for group M18-416

Thu, 20 Dec	14:30 — 16:05	TEST	English Language (Technological Terminology)  Ivanova E.G.  A-308
Mon, 24 Dec	12:45 — 14:20	ATT	Nuclear Physics  Garmash A.A.  B-214
Mon, 24 Dec	14:30 — 16:05	TEST	Interaction of RF Electromagnetic Radiation with Semiconductor Electronics Materials (Physics Principals)  Shurenkov V.V.  D-408
Mon, 24 Dec	16:15 — 17:50	ATT	Optoelectronic Devices and Systems  Voronov Y.A.  D-311
Thu, 27 Dec	12:45 — 14:20	TEST	Selected Chapters of Higher Mathematics  Trushkin N.S.  V-315
Thu, 27 Dec	14:30 — 16:05	ATT	Microelectronic Sensors and Transducers  Podlepetskiy B.I.  D-405
Thu, 27 Dec	16:15 — 17:50	ATT	Electromagnetic Compatibility (Emc)  Shurenkov V.V.  B-212
Thu, 27 Dec	17:55 — 19:30	TEST	Academic (Research) Practice  Samotaev N.N.  dep.27
Thu, 10 Jan	09:00 — 13:00	EXAM	Nuclear Physics  Garmash A.A.  V-417
Mon, 14 Jan	09:00 — 13:00	EXAM	Optoelectronic Devices and Systems  Voronov Y.A.  D-311
Fri, 18 Jan	09:00 — 13:00	EXAM	Electromagnetic Compatibility (Emc)  Shurenkov V.V.  D-311
Wed, 23 Jan	09:00 — 13:00	EXAM	Microelectronic Sensors and Transducers  Podlepetskiy B.I.  D-303